

ACCESS-FM-GG

AppNano ACCESS-FM-GG™ probes are sharp silicon probes coated with Gold on reflex and tip side for force calibration mode applications that allow a direct optical view of the AFM tip and designed for applications that require seeing the tip as it engages the surface. These probes have a medium frequency and spring constant that make them ideally suited for Force Modulation Microscopy. These probes are nanofabricated using highly doped single crystal silicon with unparalleled reproducibility, robustness and sharpness for consistent high resolution imaging.

Tip Specifications

- **Material:** Silicon
- **Shape:** Triangular Pyramid
- **Height (µm):** 14-16
- **ROC (nm) :** 30
- **Coating:** Gold



[ACCESS-FM-GG](#)

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Cantilever Specifications

Material: Silicon

Shape : Rectangular

Reflex
coating : Gold

Parameter	Nominal	Min	Max
k (N/m)	2.7	0.8	8.9
f (kHz)	60.0	36.0	98.0
Length (µm)	245.0	225.0	265.0
Width (µm)	52.0	51.0	53.0
Thickness (µm)	2.80	1.80	3.80